

Notice of References Cited	Application/Control No. 10/530,759		Applicant(s)/Patent Under Reexamination LEPPANEN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0035594 A1	03-2002	DREKE et al.	709/203
*	B	US-2003/0073440 A1	04-2003	Mukherjee et al.	455/435
*	C	US-2003/0110228 A1	06-2003	Xu et al.	709/207
*	D	US-2003/0217142 A1	11-2003	Bobde et al.	709/224
*	E	US-2004/0059781 A1	03-2004	Yoakum et al.	709/204
*	F	US-2004/0062383 A1	04-2004	Sylvain, Dany	379/265.06
*	G	US-2004/0064568 A1	04-2004	Arora et al.	709/228
*	H	US-2004/0260944 A1	12-2004	Maanoja et al.	713/201
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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